

| | | | | |
|-----------------------------------|--|-------------------------|---|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/622,265 | WU ET AL. | |
| Examiner Jayprakash N Gandhi | | Art Unit 2125 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,574,621 | 06-2003 | Lautzenheiser et al. | 707/4 |
| * | B | US-6,526,387 | 02-2003 | Ruffin et al. | 705/7 |
| * | C | US-6,470,227 | 10-2002 | Rangachari et al. | 700/95 |
| * | D | US-6,292,792 | 09-2001 | Baffles et al. | 706/45 |
| * | E | US-6,226,792 | 05-2001 | Goiffon et al. | 717/120 |
| * | F | US-5,978,594 | 11-1999 | Bonnell et al. | 710/17 |
| * | G | US-5,487,135 | 01-1996 | Freeman, Paul R. W. | 706/59 |
| * | H | US-5,233,513 | 08-1993 | Doyle, William P. | 705/7 |
| * | I | US-4,930,071 | 05-1990 | Tou et al. | 707/4 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.